## Notice of References Cited

	44. F. F.	
Application/Control No.	Applicant(s)/Par Reexamination	tent Under
09/989,519	Reexamination RAITHEL ET AI	L.
Examiner	Art Unit	
Uven T Le	2171	Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,434,455	08-2002	Snow et al.	701/33
	В	US-6,208,919	03-2001	Barkesseh et al.	701/35
	С	US-			
	Ď	US-			
	Ε	US-			
	F	US-		_	
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	w				
	x				

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